

## 3 Channel, 16-Bit, 81 MSPS Analog Front End with LVDS/ CMOS Output, Integrated CCD/CIS Sensor Timing Generator and SSCG

#### **General Description**

The LM98725 is a fully integrated, high performance 16-Bit, 81 MSPS signal processing solution for digital color copiers, scanners, and other image processing applications. Highspeed signal throughput is achieved with an innovative architecture utilizing Correlated Double Sampling (CDS), typically employed with CCD arrays, or Sample and Hold (S/H) inputs (for higher speed CCD or CMOS image sensors). The signal paths utilize 8 bit Programmable Gain Amplifiers (PGA), a +/-9-Bit offset correction DAC and independently controlled Digital Black Level correction loops for each input. The PGA and offset DAC are programmed independently allowing unique values of gain and offset for each of the three inputs. The signals are then routed to a 81MHz high performance analog-to-digital converter (ADC). The fully differential processing channel shows exceptional noise immunity, having a very low noise floor of -74dB. The 16-bit ADC has excellent dynamic performance making the LM98725 transparent in the image reproduction chain.

A very flexible integrated SSCG (Spread Spectrum Clock Generation) modulator is included to assist with EM compliance and reduce system costs.

### **Applications**

- Multi-Function Peripherals
- Facsimile Equipment
- Flatbed or Handheld Color Scanners
- High-speed Document Scanner

#### **Features**

- LVDS/CMOS Outputs
- LVDS/CMOS/Crystal Clock Source with PLL Multiplication
- Integrated Flexible Spread Spectrum Clock Generation
- CDS or S/H Processing for CCD or CIS sensors
- Independent Gain/Offset Correction for Each Channel
- Automatic Gain and Offset for for Each Channel
- Programmable Input Clamp Voltage
- Flexible CCD/CIS Sensor Timing Generator

### **Key Specifications**

Maximum Input Level	1.2 or 2.4 Volt Modes
8	(both with + or - polarity option)
<ul> <li>ADC Resolution</li> </ul>	16-Bit
<ul> <li>ADC Sampling Rate</li> </ul>	81 MSPS
∎ INL	+17/- 28 LSB (typ)
Channel Sampling Rate	e 30/30/27 MSPS
PGA Gain Steps	256 Steps
PGA Gain Range	0.62 to 8.3x
Analog DAC Resolution	+/-9 Bits
Analog DAC Range	+/-307mV or +/-614mV
<ul> <li>Digital DAC Resolution</li> </ul>	+/-6 Bits
<ul> <li>Digital DAC Range</li> </ul>	-2048 LSB to + 2016 LSB
■ SNR	-74dB (@0dB PGA Gain)
<ul> <li>Power Dissipation</li> </ul>	755mW (LVDS)
<ul> <li>Operating Temp</li> </ul>	0 to 70°C
Supply Voltage	3.3V Nominal (3.0V to 3.6V range)

### System Block Diagram











Pir www.	Pin Descriptions www.DataSheet4U.com									
Pin	Name	I/O	Тур	Res		Description				
1	PHIC2	0	D	PU	Configurable high speed	ed sensor timing output.				
2	PHIC1	0	D	PD	Configurable high speed	ed sensor timing output.				
3	SH1	0	D	PU	Configurable low speed	d sensor timing output.				
4	CE	I	D		Chip Serial Interface Add	ddress Setting Input				
					CE Level	Address				
					V <sub>D</sub>	01				
					Float	10				
					DGND	00				
5	CAL	I	D	PD	Initiate calibration seque	ence. Leave unconnected or tie to DGND if unused.				
6	RESET	1	D	PU	Active-low master reset.	t. NC when function not being used.				
7	SH_R	I	D	PD	External request for an S	SH interval.				
8	SDI	I	D	PD	Serial Interface Data Inp	put.				
9	SDO	0	D		Serial Interface Data Out	utput.				
10	SCLK	I	D	PD	Serial Interface shift regi	gister clock.				
11	SEN	I	D	PU	Active-low chip enable for the Serial Interface.					
12	V <sub>A</sub>		Р		Analog power supply. Bypass voltage source with 4.7 $\mu$ F and pin with 0.1 $\mu$ F to AGND.					
13	AGND		Р		Analog ground return.					
14	V <sub>A</sub>		Р		Analog power supply. Bypass voltage source with $4.7\mu F$ and pin with $0.1\mu F$ to AGND.					
15	VREFB	0	А		Bottom of ADC reference	ce. Bypass with a 0.1µF capacitor to ground.				
16	VREFT	0	A		Top of ADC reference. B	Bypass with a 0.1µF capacitor to ground.				
17	VA		Р		Analog power supply. Bypass voltage source with $4.7\mu$ F and pin with $0.1\mu$ F to AGND.					
18	AGND		Р		Analog ground return.					
19	VCLP	Ю	A		Input Clamp Voltage. Normally bypassed with a 0.1µF , and a 4.7µF capacitor to AGND. An external reference voltage may be applied to this pin.					
20	V <sub>A</sub>		Р		Analog power supply. By	Bypass voltage source with $4.7\mu$ F and pin with $0.1\mu$ F to AGND.				
21	IBIAS	0	A		Bias setting pin. Connect	ect a 9.0 kOhm 1% resistor to AGND.				
22	AGND		Р		Analog ground return.					
23	OS <sub>R</sub>	I	А		Analog input signal. Typi	pically sensor Red output AC-coupled thru a capacitor.				
24	AGND		Р		Analog ground return.					
25	OS <sub>G</sub>	I	A		Analog input signal. Typi	pically sensor Green output AC-coupled thru a capacitor.				
26	AGND		Р		Analog ground return.					
27	OS <sub>B</sub>	1	А		Analog input signal. Typi	pically sensor Blue output AC-coupled thru a capacitor.				
28	CPOFILT2		A		Charge Pump Filter Cap CPOFILT1.	pacitor. Bypass this supply pin with a 0.1µF capacitor to				
29	DGND		Р		Digital ground return.					
30	CPOFILT1		A		Charge Pump Filter Cap CPOFILT2.	pacitor. Bypass this supply pin with a $0.1\mu F$ capacitor to				
31	DVB	0	D		Digital Core Voltage byp	pass. Not an input. Bypass with 0.1µF capacitor to DGND.				
32	INCLK+	1	D		Clock Input. Non-Invertin	ting input for LVDS clocks or CMOS clock input. CMOS clock is				
					selected when pin 29 is h	held at DGND, otherwise clock is configured for LVDS operation.				
33	INCLK-	1	D		Clock Input. Inverting inp	nput for LVDS clocks, connect to DGND for CMOS clock.				
34	DOUT7/	0	D		Bit 7 of the digital video o	output bus in CMOS Mode, LVDS Frame Clock+ in LVDS Mode.				
_	TXCLK+									
35	DOUT6/ TXCLK-	0	D		Bit 6 of the digital video o	output bus in CMOS Mode, LVDS Frame Clock- in LVDS Mode.				
36	DOUT5/	0	D		Bit 5 of the digital video of	o output bus in CMOS Mode, LVDS Data Out2+ in LVDS Mode.				
	TXOUT2+									

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	News		<b>T</b>	Dee	Description
Pin ataShe	Name et4U.com	1/0	тур	Res	Description
37	DOUT4/	0	D		Bit 4 of the digital video output bus in CMOS Mode, LVDS Data Out2- in LVDS Mode.
	TXOUT2-				
38	DOUT3/	0	D		Bit 3 of the digital video output bus in CMOS Mode, LVDS Data Out1+ in LVDS Mode.
	TXOUT1+				
39	DOUT2/	0	D		Bit 2 of the digital video output bus in CMOS Mode, LVDS Data Out1- in LVDS Mode.
	TXOUT1-				
40	DOUT1/	0	D		Bit 1 of the digital video output bus in CMOS Mode, LVDS Data Out0+ in LVDS Mode.
	TXOUT0+				
41	DOUT0/	0	D		Bit 0 of the digital video output bus in CMOS Mode, LVDS Data Out0- in LVDS Mode.
	TXOUT0-				
42	DGND	0	D	PD	Configurable sensor control output.
43	V <sub>D</sub>		Р		Power supply for the digital circuits. Bypass this supply pin with $0.1\mu$ F capacitor. A single
					4.7μF capacitor should be used between the supply and the VD, VR and VC pins.
44	V <sub>C</sub>		Р		Power supply for the sensor control outputs. Bypass this supply pin with $0.1\mu\text{F}$ capacitor.
45	CLKOUT/SH2	0	D		Output clock for registering output data when using CMOS outputs, or a configurable
					low speed sensor timing output.
46	SH3	0	D		Configurable low speed sensor timing output.
47	RS	0	D		Configurable high speed sensor timing output.
48	СР	0	D		Configurable high speed sensor timing output.
49	PHIA1	0	D		Configurable high speed sensor timing output.
50	PHIA2	0	D		Configurable high speed sensor timing output.
51	DGND		Р		Digital ground return.
52	V <sub>c</sub>		Р		Power supply for the sensor control outputs.
					Bypass this supply pin with 0.1µF capacitor.
53	PHIB1	0	D		Configurable high speed sensor timing output.
54	PHIB2	0	D		Configurable high speed sensor timing output.
55	SH4	0	D		Configurable low speed sensor timing output.
56	SH5	0	D		Configurable low speed sensor timing output.
	1			1	

(I=Input), (O=Output), (IO=Bi-directional), (P=Power), (D=Digital), (A=Analog), (PU=Pull Up with an internal resistor), (PD=Pull Down with an internal resistor.).

#### Absolute Maximum Ratings (Notes 1, 2) WWW.DataSheet4U.com If Military/Aerospace specified devices are required,

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

4.2V
–0.3V to
(VA + 0.3V)
-0.3V to
(VA + 0.3V)
2.0V
±25 mA
±50 mA
150°C
<66°C/W

Package Dissipation at T <sub>A</sub> = 25°C (Note 4)	>1.89W
ESD Rating (Note 5)	
Human Body Model	2500V
Machine Model	250V
Storage Temperature	–65°C to +150°C
Soldering process must comply with Na Semiconductor's Reflow Temperature F specifications. Refer to www.national.cc (Note 6)	tional Profile om/packaging.

### **Operating Ratings** (Notes 1, 2)

Operating Temperature Range	$0^{\circ}C \le T_A \le +70^{\circ}C$
All Supply Voltage	+3.0V to +3.6V

#### **Electrical Characteristics**

The following specifications apply for VA = VD = VR = VC = 3.3V,  $C_L$  = 10pF, and  $f_{INCLK}$  = 27MHz unless otherwise specified. Boldface limits apply for  $T_A = T_{MIN}$  to  $T_{MAX}$ ; all other limits  $T_A$  = 25°C.

Symbol	Parameter	Conditions	Min (Note 9)	Typ (Note 8)	Max (Note 9)	Units
CMOS Digit	al Input DC Specifications (RESETb,	SH_R, SCLK, SENb)	•			
V <sub>IH</sub>	Logical "1" Input Voltage		2.0			V
V <sub>IL</sub>	Logical "0" Input Voltage				0.8	V
VIHYST	Logic Input Hysteresis			0.6		
I <sub>IH</sub>	Logical "1" Input Current	V <sub>IH</sub> = VD				
		RESET, SEN		100		nA
		SH_R, SCLK, SDI, CAL		65		μA
		CE		30		nA
I <sub>IL</sub>	Logical "0" Input Current	$V_{IL} = DGND$				
		RESETSEN		-65		μA
		SH_R, SCLK, SDI, CAL		-100		nA
		CE		-30		μA
CMOS Digit	al Output DC Specifications (SH1 to	SH5, RS, CP, PHIA, PHIB, PHIC	;)			
V <sub>OH</sub>	Logical "1" Output Voltage	I <sub>OUT</sub> = -0.5mA	3.0			V
V <sub>OL</sub>	Logical "0" Output Voltage	l <sub>OUT</sub> = 1.6mA			0.21	V
Ios	Output Short Circuit Current	V <sub>OUT</sub> = DGND		18		mA
		V <sub>OUT</sub> = VD		-25		
I <sub>oz</sub>	CMOS Output TRI-STATE Current	V <sub>OUT</sub> = DGND		20		nA
		$V_{OUT} = VD$		-25		
CMOS Digit	al Output DC Specifications (CMOS	Data Outputs)				
V <sub>OH</sub>	Logical "1" Output Voltage	I <sub>OUT</sub> = -0.5mA		2.3		V
V <sub>OL</sub>	Logical "0" Output Voltage	l <sub>OUT</sub> = 1.6mA		0.12		V
I <sub>OS</sub>	Output Short Circuit Current	V <sub>OUT</sub> = DGND		12		mA
		V <sub>OUT</sub> = VD		-14		
I <sub>oz</sub>	CMOS Output TRI-STATE Current	V <sub>OUT</sub> = DGND		20		nA
		$V_{OUT} = VD$		-25		
LVDS/CMO	S Clock Receiver DC Specifications (	INCLK+ and INCLK- Pins)				

ata <b>Symeter</b> 4U	.com Parameter	Conditions	Min (Note 9)	<b>Typ</b> (Note 8)	Max (Note 9)	Ur
V <sub>IHL</sub>	Differential LVDS Clock	R <sub>1</sub> = 100Ω			200	n
	High Threshold Voltage	V <sub>CM</sub> (LVDS Input Common Mode Voltage)= 1.25V				
V <sub>ILL</sub>	Differential LVDS Clock		-200			n
V			2.0			,
IHC	High Threshold Voltage		2.0			
V	CMOS Clock				0.8	,
• ILC	I ow Threshold Voltage				0.0	
	CMOS Clock			230	260	1
ILL	Input High Current					۲
	CMOS Clock		-135	-120		L
ILC	Input Low Current					٢
LVDS Outp	ut DC Specifications					
V <sub>OD</sub>	Differential Output Voltage	R <sub>L</sub> = 100Ω	280	390	490	rr
V <sub>OS</sub>	LVDS Output Offset Voltage		1.08	1.20	1.33	,
I <sub>os</sub>	Output Short Circuit Current	$V_{OUT} = 0V, R_1 = 100\Omega$		8.5		n
Power Sup	ply Specifications				1	
IA	VA Analog Supply Current	LVDS Output Data Format		152	180	n
		LVDS Output Data Format		3.6	6	n
		(Powerdown)				
		CMOS Output Data Format		136	168	n
		(40 MHz)				
ID	VD Digital Output Driver Supply	LVDS Output Data Format		76	94	rr
	Current	LVDS Output Data Format (Powerdown)		8.5	17	r
		CMOS Output Data Format (ATE Loading of CMOS Outputs > 50 pF) (40 MHz)		46	68	rr
IC	VC CCD Timing Generator Output Driver Supply Current	Typical sensor outputs: SH1-SH5, PHIA, PHIB, PHIC, RS, CP (ATE Loading of CMOS Outputs > 50pF)		1	4	m
PWR	Average Power Dissipation	LVDS Output Data Format		755	885	m
		LVDS Output Data Format (Powerdown)		40	70	m
		CMOS Output Data Format (ATE Loading of CMOS Outputs > 50pF) (40 MHz)		600	740	m
Input Samp	ling Circuit Specifications					
V <sub>IN</sub>	Input Voltage Level	CDS Gain=1x, PGA Gain=1x		2.3		Vp
		CDS Gain=2x. PGA Gain= 1x		1.22		

w <b>\$W#!!!!</b> ata	Sheet4U.congrameter	Conditions	Min (Note 9)	<b>Typ</b> (Note 8)	Max (Note 9)	Units
I <sub>IN_SH</sub>	Sample and Hold Mode	Source Followers Off		32	50	μA
	Input Leakage Current	CDS Gain = 1x	(-200)	(-165)		
		$OS_X = VA (OS_X = AGND)$				
		Source Followers Off		55	70	μA
		CDS Gain = 2x	(-290)	(-240)		
		$OS_X = VA (OS_X = AGND)$				
		Source Followers On		20	250	nA
		CDS Gain = 2x	(-250)	(-50)		
		$OS_X = VA (OS_X = AGND)$				
Ссн	Sample/Hold Mode	CDS Gain = 1x		2.5		pF
311	Equivalent Input Capacitance					
		CDS Gain = 2x		4		pF
	CDS Mode	Source Followers Off		10	250	nA
-IIN_CD5	Input Leakage Current	$OS_{\times} = VA (OS_{\times} = AGND)$	(-250)	(-50)		
B	CI PIN Switch Besistance		( /	16	55	0
' 'CLPIN	(OS., to VCLP Node)			10	00	52
		VCL P Voltago Sotting - 000		0 95\//		V
		VCLP Voltage Setting 001		0.05VA		V
		VCLP Voltage Setting = 001		0.9VA		V
		VCLP Voltage Setting = 010		0.95VA		V
V <sub>VCLP</sub>	VCLP Voltage 011	VCLP Voltage Setting = 011		0.6VA		V
-	VCLP Voltage 100	VCLP Voltage Setting = 100		0.55VA		V
	VCLP Voltage 101	VCLP Voltage Setting = 101		0.4VA		V
	VCLP Voltage 110	VCLP Voltage Setting = 110		0.35VA		V
	VCLP Voltage 111	VCLP Voltage Setting = 111		0.15VA		V
I <sub>SC</sub>	VCLP DAC Short Circuit Output	0001 xxxxb VCLP Config.		30		mA
	Current	Register =				
Black Level	Offset DAC Specifications	1			1	r
	Resolution			10		Bits
	Monotonicity		Gi	uaranteed by	characteriza	tion
	Offset Adjustment Range	CDS Gain = 1x				
	Referred to AFE Input	Minimum DAC Code = 0x000		-614		mV
		Maximum DAC Code = 0x3FF		614		
		CDS Gain = 2x				
		Minimum DAC Code = 0x000		-307		mV
		Maximum DAC Code = 0x3FF		307		
	Offset Adjustment Range	Minimum DAC Code = 0x000	-17500		-16130	
	Referred to AFE Output	Maximum DAC Code = 0x3FF	+16130		+17500	LOD
	DAC LSB Step Size	CDS Gain = 1x		1.2		mV
		Referred to AFE Output		(32)		(LSB)
DNL	Differential Non-Linearity		-0.84	+0.74/ -0.37	+2.4	LSB
INL	Integral Non-Linearity		-2.5	+0.72/ -0.56	+2.5	LSB
		L	1		I	I
PGA Specif	ications					
PGA Specif	Gain Resolution			8		Bits
PGA Specif	ications Gain Resolution Monotonicity		Gi	8 Jaranteed bv	characteriza	Bits
PGA Specif	ications Gain Resolution Monotonicity Maximum Gain	CDS Gain = 1x	Gu 7.7	8 Jaranteed by 8.3	characteriza 8.8	Bits tion V/V

ata <b>Symeter</b> 4U	.com Parameter	Conditions	Min (Note 9)	Typ (Note 8)	Max (Note 9)	Units
	Minimum Gain	CDS Gain = 1x	0.58	0.62	0.67	V/V
		CDS Gain = 1x	-4.7	-4.2	-3.5	dB
	PGA Function	Gain (V/V	) = (196/(28	30-PGA Code	e))	
		Gain (dB) = 20	LOG10(19	6/(280-PGA (	Code))	
	Channel Matching	Minimum PGA Gain		3		%
		Maximum PGA Gain		12.7		
ADC Specif	ications					
$V_{REFT}$	Top of Reference			2.07		V
V <sub>REFB</sub>	Bottom of Reference			0.89		V
V <sub>REFT</sub> - V <sub>REFB</sub>	Differential Reference Voltage		1.06	1.18	1.30	V
	Overrange Output Code			65535		
	Underrange Output Code			0		
Digital Offs	et "DAC" Specifications		•		•	•
	Resolution			7		Bits
	Digital Offset DAC LSB Step Size	Referred to AFE Output		32		LSB
	Offset Adjustment Range	Min DAC Code =7b0000000		-2048		
	Referred to AFE Output	Mid DAC Code =7b1000000		0		LSB
		Max DAC Code = 7b1111111		+2016		
Full Channe	el Performance Specifications			-		
DNL	Differential Non-Linearity	(Note 10)	-0.999	+0.8/-0.7	2.5	LSB
INL	Integral Non-Linearity	(Note 10)	-75	+18/-25	75	LSB
		Minimum PGA Gain		-76		dB
	Total Output Naisa	(Note 10)		10	26	LSB RM
SINK	Total Output Noise	Maximum PGA Gain		-56		dB
		(Note 10)		96		LSB RM
	Channel to Channel Crosstalk	Mode 3		26		
		Mode 2		17		

### wACDTiming4Specifications

The following specifications apply for VA = VD = VR = VC = 3.3V,  $C_L = 10pF$ , and  $f_{INCLK} = 27MHz$  unless otherwise specified. Boldface limits apply for  $T_A = T_{MIN}$  to  $T_{MAX}$ ; all other limits  $T_A = 25^{\circ}C$ .

Symbol	Parameter	Conditions	Min (Note 9)	<b>Typ</b> (Note 8)	Max (Note 9)	Units
Input Clo	ck Timing Specifications	•				
		INCLK = PIXCLK (Pixel Rate Clock)	0.66 1 1		15 (Mode 3) 22.5 (Mode 2) 30 (Mode 1)	MHz
f <sub>INCLK</sub>	Input Clock Frequency	INCLK = ADCCLK (ADC Rate Clock)	2		45 (Mode 3) 45 (Mode 2) 30 (Mode 1)	MHz
T <sub>dc</sub>	Input Clock Duty Cycle		40/60	50/50	60/40	%
Full Chan	nel Latency Specifications					
	SH out to First Sampled Pixel	PIXPHASE0 PIXPHASE1		0		
		PIXPHASE2		1		
t <sub>SHFP</sub>		PIXPHASE3		1 1/2		T <sub>ADC</sub>
		PIXPHASE4		2		
		PIXPHASE5		2 1/2		
	3 Channel Mode Pipeline Delay	PIXPHASE0		22		
		PIXPHASE1		21 1/2		
		PIXPHASE2		21		-
ι <sub>lat3</sub>		PIXPHASE3		20 1/2		ADC
		PIXPHASE4		20		
		PIXPHASE5		19 1/2		
	2 Channel Mode Pipeline Delay	PIXPHASE0		20		
+		PIXPHASE1		19 1/2		т
LAT2		PIXPHASE2		19		ADC
		PIXPHASE3		18 1/2		
	1 Channel Mode Pipeline Delay	PIXPHASE0		18		
t		PIXPHASE1		17 1/2		Т
'LAT1		PIXPHASE2		17		ADC
		PIXPHASE3		16 1/2		
	SH out to First Valid Data	Mode 3		22		
t <sub>SHFD</sub>	(t <sub>SHFP</sub> + t <sub>LATx</sub> )	Mode 2		20		T <sub>ADC</sub>
	(PIXPHASE0)	Mode 1		18		
SH_R Tim	ning Specifications	1	1			
t <sub>SHR_S</sub>	SH_R Setup Time			2		ns
<sup>t</sup> <sub>SHR_H</sub>	SH_R Hold Time			2		ns
	tput Timing Specifications				0.00	
	I XCLK to Pulse Position 0	LVDS Output	-0.26	0	0.26	ns
	I XCLK to Pulse Position 1	Specifications not	1.50	1.76	2.02	ns
IX <sub>pp2</sub>	I XCLK to Pulse Position 2	tested in production.	3.26	3.53	3.79	ns
IX <sub>pp3</sub>	FXCLK to Pulse Position 3	Min/Max guaranteed	5.03	5.29	5.55	ns
TX <sub>pp4</sub>	TXCLK to Pulse Position 4	by design,	6.80	7.06	7.32	ns
TX <sub>pp5</sub>	TXCLK to Pulse Position 5	characterization and statistical	8.56	8.82	9.08	ns
TX <sub>pp6</sub>	TXCLK to Pulse Position 6	analysis.	10.32	10.58	10.84	ns

t <b>synco</b> t4	U.com Parameter	Conditions	Min (Note 9)	Typ (Note 8)	Max (Note 9)	Unit
	tput Timing Specifications			<u> </u>		1
t <sub>CRDO</sub>	CLKOUT Rising Edge to CMOS Output Data Transition	t <sub>INCLK</sub> = 40MHz INCLK = ADCCLK (ADC Rate Clock)	2	4.5	9	ns
Serial Inte	erface Timing Specifications					
f <sub>SCLK</sub>	Input Clock Frequency	f <sub>SCLK</sub> <= f <sub>INCLK</sub> INCLK = PIXCLK (Pixel Rate Clock) Mode 3/2/1			27/30/30	МН
		f <sub>SCLK</sub> <= f <sub>INCLK</sub> INCLK = ADCCLK (ADC Rate Clock) Mode 3/2/1			81/60/30	МН
	SCLK Duty Cycle			50/50		ns
t <sub>IH</sub>	Input Hold Time		1.5			ns
t <sub>IS</sub>	Input Setup Time		2.5			ns
t <sub>SENSC</sub>	SCLK Start Time After SEN Low		1.5			ns
t <sub>SCSEN</sub>	SEN High after last SCLK Rising Edge		2.5			ns
t <sub>SENW</sub>	SEN Pulse Width	INCLK present INCLK stopped (Notes 11, 12)	6 50			T <sub>INC</sub> ns
t <sub>OD</sub>	Output Delay Time	· · · · · ·		11	14	ns
t <sub>H7</sub>	Data Output to High Z				0.5	T <sub>SC</sub>

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions. Operation of the device beyond the Operating Ratings is not recommended.

Note 2: All voltages are measured with respect to AGND = DGND = 0V, unless otherwise specified.

**Note 3:** When the input voltage  $(V_{IN})$  at any pin exceeds the power supplies  $(V_{IN} < GND \text{ or } V_{IN} > V_A \text{ or } V_D)$ , the current at that pin should be limited to 25 mA. The 50 mA maximum package input current rating limits the number of pins that can simultaneously safely exceed the power supplies with an input current of 25 mA to two.

**Note 4:** The maximum power dissipation must be derated at elevated temperatures and is dictated by  $T_{JMAX}$ ,  $\theta_{JA}$  and the ambient temperature,  $T_A$ . The maximum allowable power dissipation at any temperature is  $P_D = (T_{JMAX} - T_A)/\theta_{JA}$ . The values for maximum power dissipation listed above will be reached only when the device is operated in a severe fault condition (e.g. when input or output pins are driven beyond the power supply voltages, or the power supply polarity is reversed). Such conditions should always be avoided.

Note 5: Human body model is 100 pF capacitor discharged through a 1.5 k $\Omega$  resistor. Machine model is 220 pF discharged through 0 $\Omega$ .

Note 6: Reflow temperature profiles are different for lead-free and non-lead-free packages.

Note 7: The analog inputs are protected as shown below. Input voltage magnitudes beyond the supply rails will not damage the device, provided the current is limited per note 3. However, input errors will be generated If the input goes above VA and below AGND.



Note 8: Typical figures are at T<sub>A</sub> = 25°C, and represent most likely parametric norms at the time of product characterization. The typical specifications are not guaranteed.

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Note 9: Test limis are guaranteed to National's AOQL (Average Outgoing Quality Level).

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Note 11: If the input INCLK is divided down to a lower internal clock rate via the PLL, the parameter t<sub>SENW</sub> will be increased by the same factor.

Note 12: When the Spread Spectrum Clock Generation feature is enabled,  $t_{SENW}$  should be increased by 1.



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## Notes

LM98725 3 Channel, 16-Bit, 81 MSPS Analog Front End with LVDS/CMOS Outpu

# Notes

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